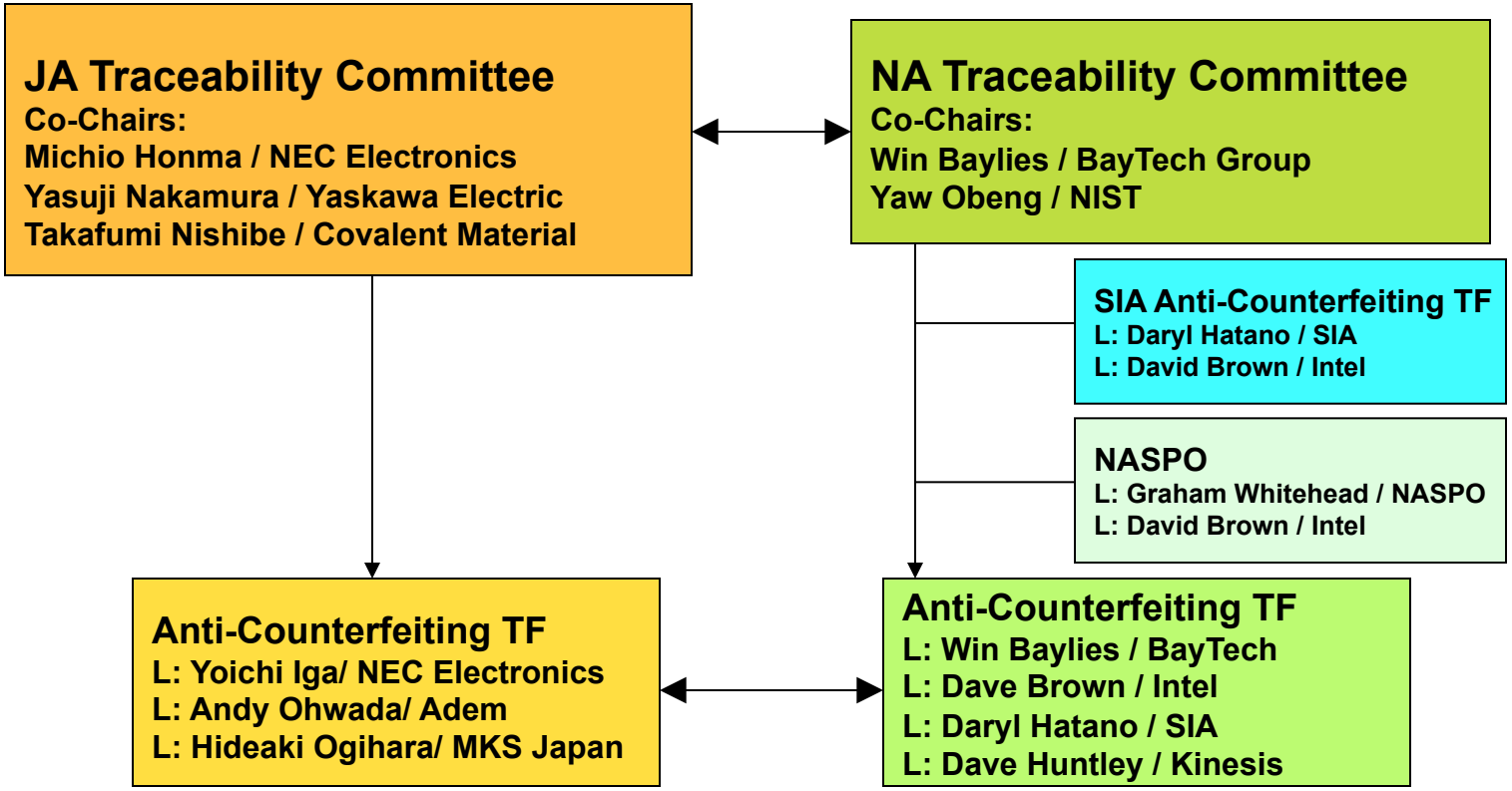
SEMI Standards Anti-Counterfeiting Task Force

Dr. Yaw Obeng, Co-Chair of NA Traceability Committee

NIST Product Authentication Information Management Workshop
February 17-18, 2009

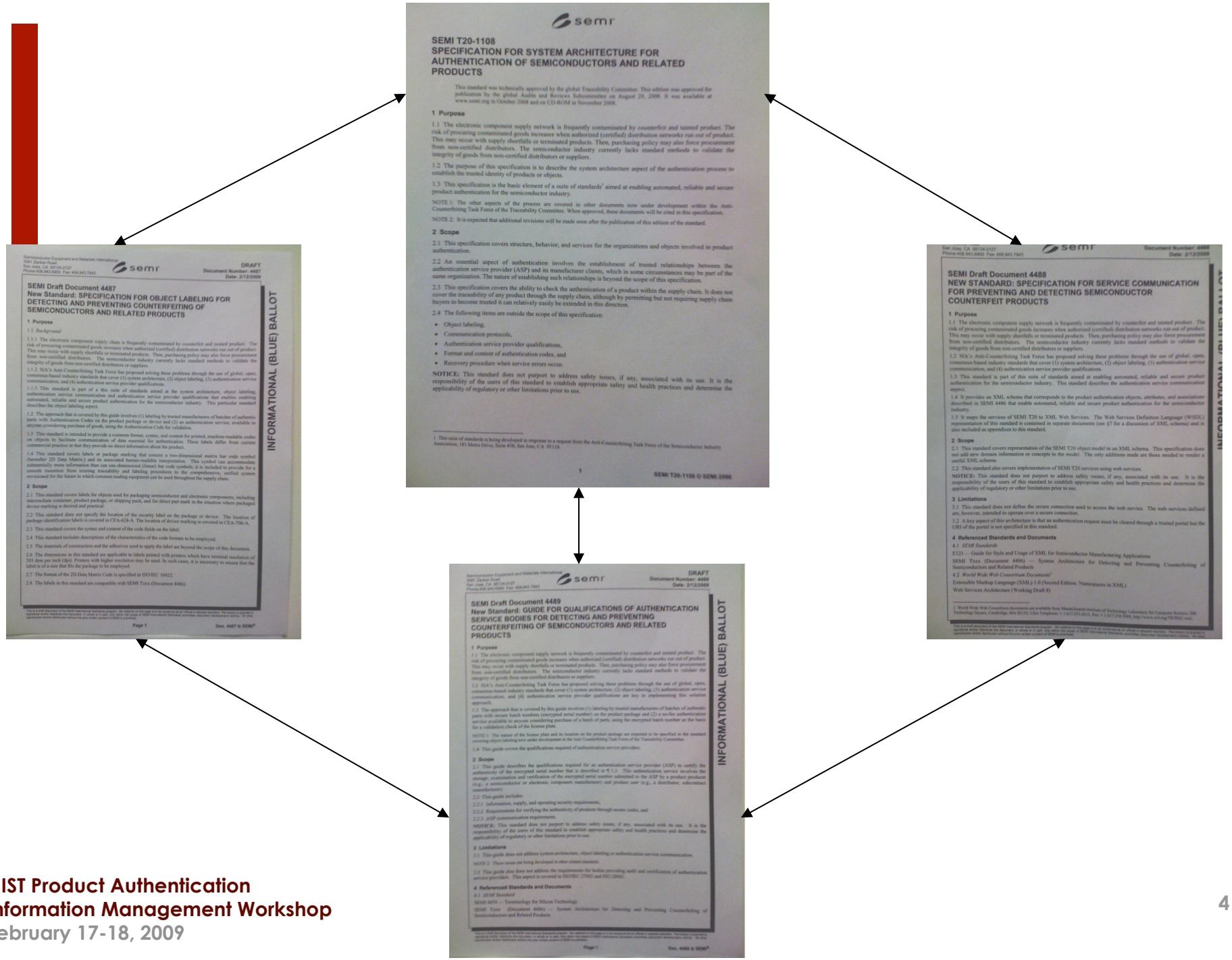
International Leadership & Support



Meeting Information

- Recent meetings
  - October 14, 2008 in San Jose, CA (SEMI HQ Office)
  - December 3, 2008 in Makuhari Japan (SEMICON Japan)

- Next meetings
  - April 2, 2009 in Milpitas, CA (Sheraton-San Jose)
  - July 16th, 2009 in San Francisco (SEMICON West)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SEMI T20-1108
SPECIFICATION FOR SYSTEM ARCHITECTURE FOR AUTHENTICATION OF SEMICONDUCTORS AND RELATED PRODUCTS
1 Purpose
2 Scope
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DRAFT
SEMI Draft Document 4487
New Standard: SPECIFICATION FOR OBJECT LABELING FOR DETECTING AND PREVENTING COUNTERFEITING OF SEMICONDUCTORS AND RELATED PRODUCTS
1 Purpose
2 Scope
INFORMATIONAL (BLUE) BALLOT
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SEMI Draft Document 4488
NEW STANDARD: SPECIFICATION FOR SERVICE COMMUNICATION FOR PREVENTING AND DETECTING SEMICONDUCTOR COUNTERFEIT PRODUCTS
1 Purpose
2 Scope
3 Limitations
4 Referenced Standards and Documents
INFORMATIONAL (BLUE) BALLOT
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SEMI Draft Document 4489
New Standard: GUIDE FOR QUALIFICATIONS OF AUTHENTICATION SERVICE BODIES FOR DETECTING AND PREVENTING COUNTERFEITING OF SEMICONDUCTORS AND RELATED PRODUCTS
1 Purpose
2 Scope
3 Limitations
4 Referenced Standards and Documents
INFORMATIONAL (BLUE) BALLOT

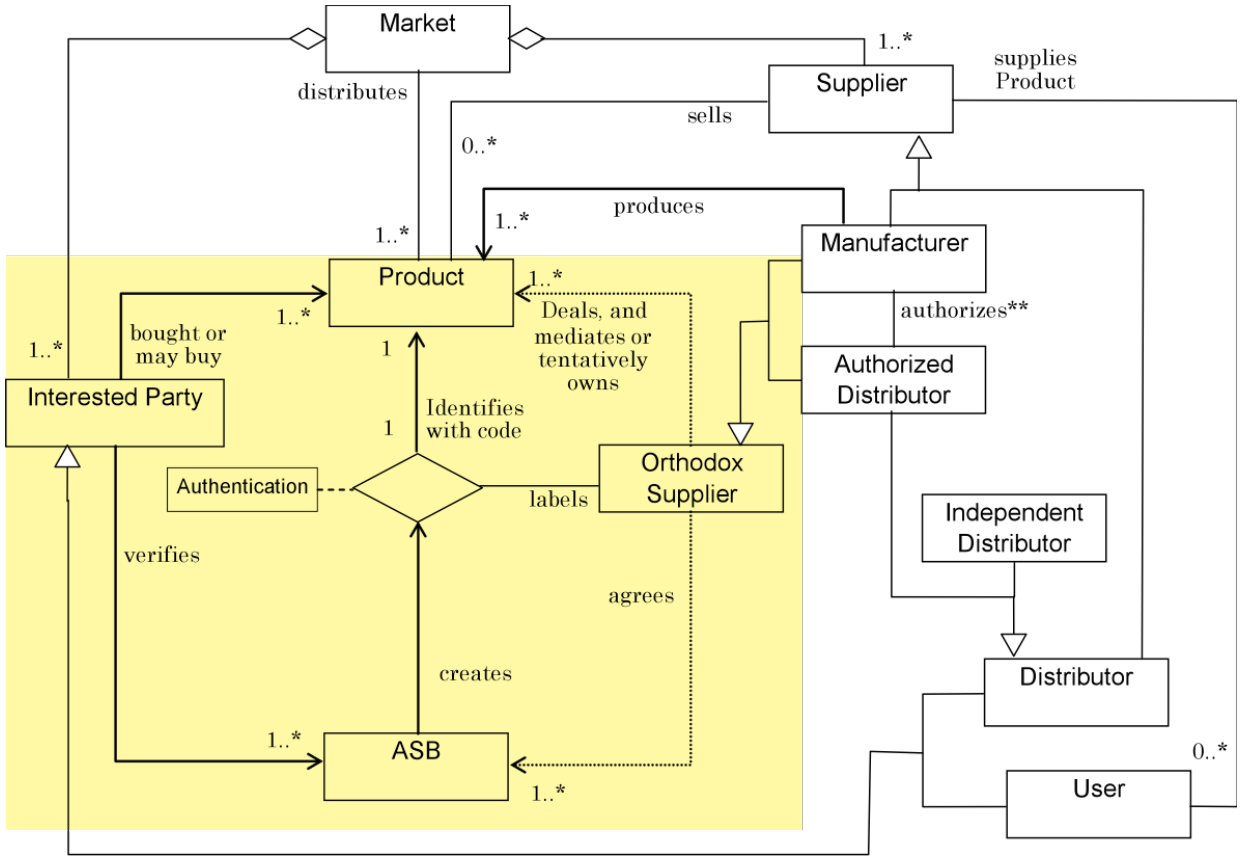
Purpose

- **Describe authentication process**
  - Ensure process is automated, reliable and secure
  - Establish trusted identity of products

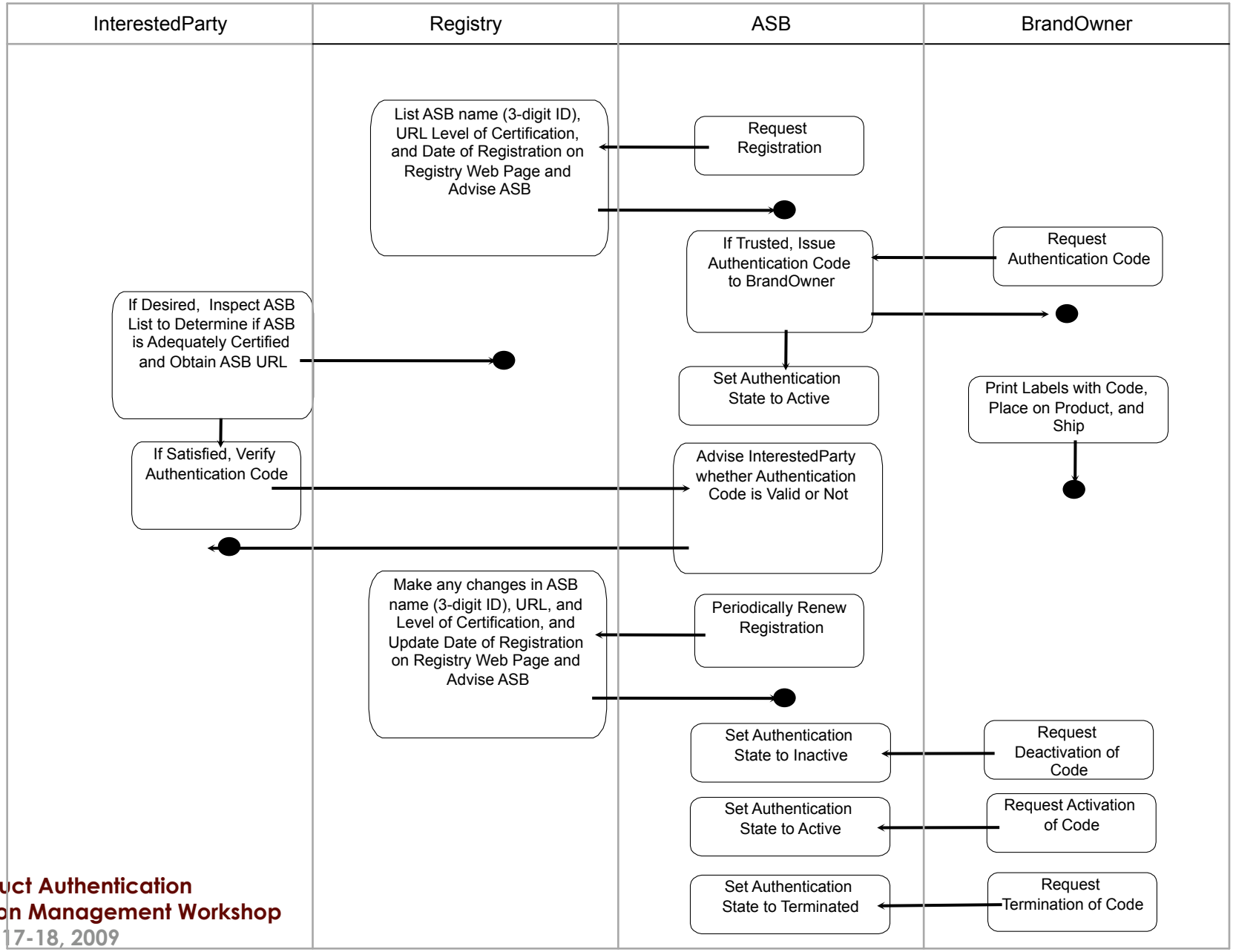
Standards

Document #	Topic	Status
T20-1108	Architectural Design	*Published*—Currently Under Revision
4487	Labeling	Under Development
4488	Authentication Service Communication	Under Development
4489	Authentication Service Body Qualifications	Under Development

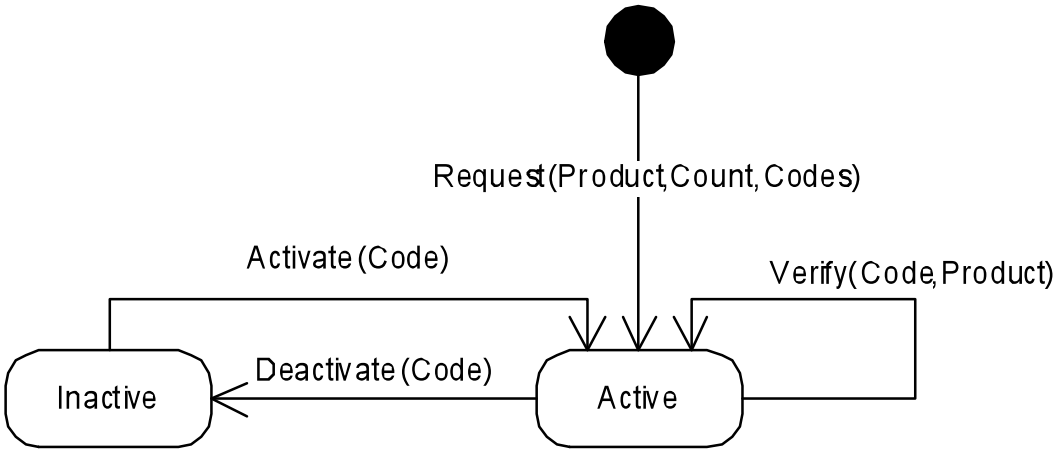
T20 Product Authentication Overview



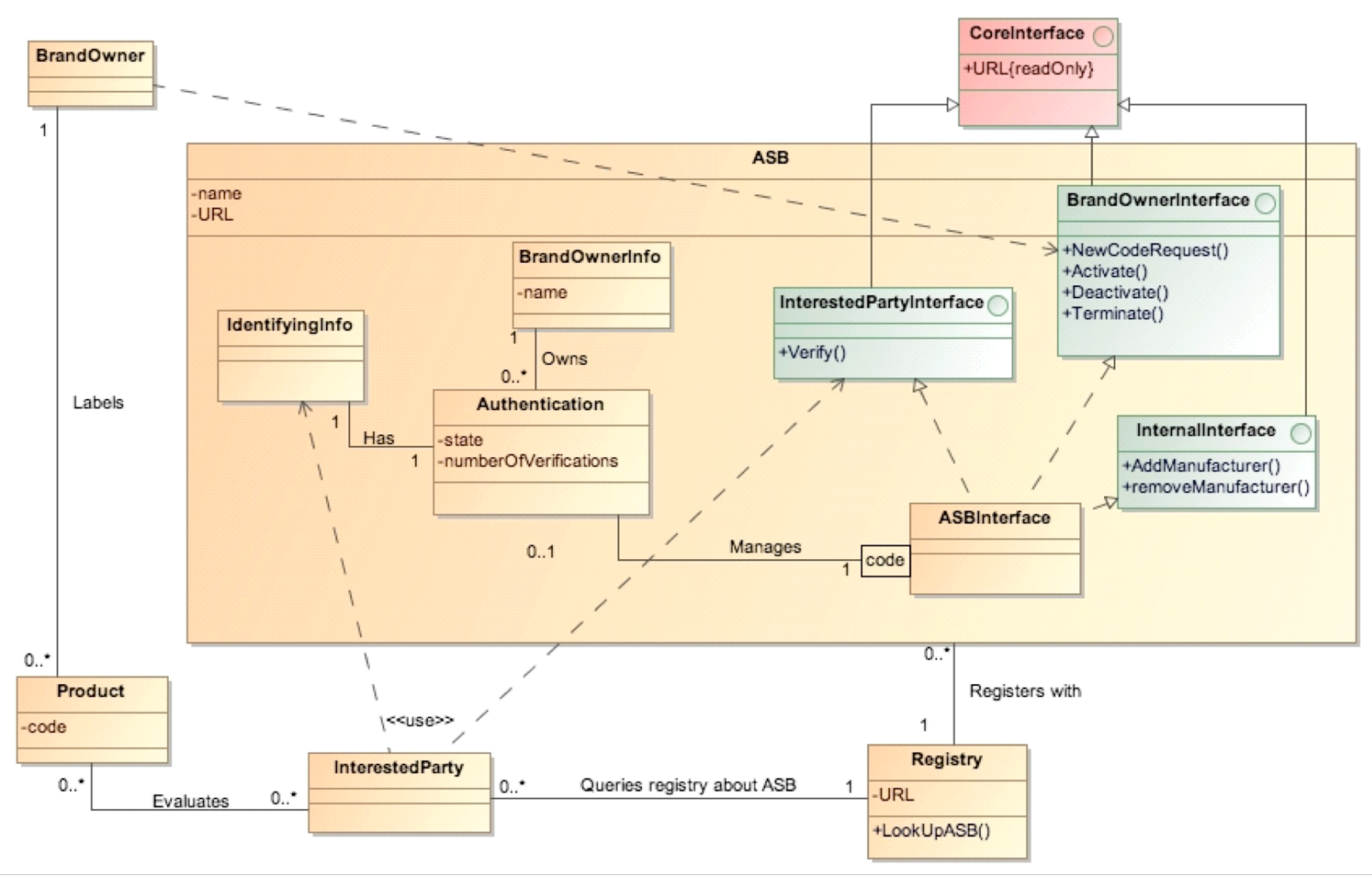
Typical Product Authentication Cycle – State Diagram



Product Authentication State Diagram



T20 Information Model



Questions / Comments?

Please contact Susan Turner (sturner@semi.org) for more information